

**Search Notes****Application/Control No.**

10/698,222

**Examiner**

Toan M. Le

**Applicant(s)/Patent under Reexamination**

SHI ET AL.

**Art Unit**

2863

**SEARCHED**

Class	Subclass	Date	Examiner
702	57	3/24/2005	TL
324	671	3/24/2005	TL
324	455	3/24/2005	TL
438	17	3/24/2005	TL
438	16	3/24/2005	TL
324	765	3/24/2005	TL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Contactless Insulating Dielectric Film Characterization	3/23/2005	TL
Substrate, Dielectric Film, Voltage, Kelvin Probe	3/23/2005	TL
Substrate, Film, Thickness, Nitrogen, Charge, Non-Contact	3/18/2005	TL
East, Web, and NPL search		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner